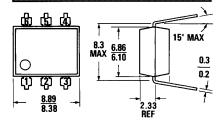
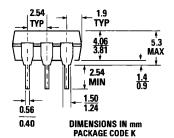


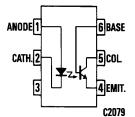
4N25 4N27 4N26 4N28

#### **PACKAGE DIMENSIONS**





ST1603A



Equivalent Circuit

#### **DESCRIPTION**

The 4N25, 4N26, 4N27, and 4N28 series of optocouplers have an NPN silicon planar phototransistor optically coupled to a gallium arsenide diode.

#### **FEATURES & APPLICATIONS**

- AC line/digital logic isolator
- Digital logic/digital logic isolator
- Telephone/telegraph line receiver
- Twisted pair line receiver
- High frequency power supply feedback control
- Relay contact monitor
- Power supply monitor
- Small package size and low cost
- Excellent frequency response
- UL recognized—File E90700

# ABSOLUTE MAXIMUM RATINGS

# TOTAL PACKAGE \*Storage temperatu

*Storage temperature	–55°C to 150°C
*Operating temperature at junction	–55°C to 100°C
*Lead temperature (soldering, 10 sec)	260°C
*Total package power dissipation at 25°C ambient (LED plus detector)	250 mW
*Derate linearly from 25°C	3.3 mW/°C

#### INPUT DIODE

*Forward DC current continuous 8	0 mA
*Reverse voltage	3.0 V
*Peak forward current	
(300 μs, 2% duty cycle)	3.0 A
*Power dissipation at 25°C ambient 150	Wm C
*Derate linearly from 25°C 2.0 m	W/°C

#### **OUTPUT TRANSISTOR**

*Collector emitter voltage (BV <sub>ceo</sub> ) 30 V
*Collector base voltage (BV <sub>CBO</sub> ) 70 V
*Emitter collector voltage (BV <sub>ECO</sub> ) 7 V
*Power dissipation at 25°C ambient 150 mW
*Derate linearly from 25°C 2.0 mW/°C

\*Indicates JEDEC Registered Data.



# ELECTRO-OPTICAL CHARACTERISTICS (25°C Free Air Temperature Unless Otherwise Specified)

INDIVIDUAL COMPONENT CHARACTERISTICS						
CHARACTERISTICS	SYMBOL	MIN.	TYP.	GUAR. MAX.	UNITS	TEST CONDITIONS
INPUT DIODE  *Forward voltage	V <sub>E</sub>		1.20	1.50		
Capacitance	C	_	150	1.50	pF	I <sub>F</sub> =10 mA V <sub>F</sub> =0 V, f=1 MHz
*Reverse leakage current			.05	100	μA	$V_R = 3.0 \text{ V}, R_L = 1.0 \text{ M}\Omega$
<b>DETECTOR</b> DC forward current gain	h <sub>FE</sub>		250		<u></u>	V <sub>CE</sub> =5 V, I <sub>C</sub> =500 μA
*Collector to emitter breakdown voltage	BV <sub>CEO</sub>	30	65		V	I <sub>c</sub> =1.0 mA, I <sub>B</sub> =0
*Collector to base breakdown voltage	BV <sub>CBO</sub>	70	165		V	I <sub>c</sub> =100 μA, I <sub>E</sub> =0
*Emitter to collector breakdown voltage	BV <sub>ECO</sub>	7	14			I <sub>E</sub> =100 μA, I <sub>B</sub> =0
*Collector to emitter leakage current (4N25, 4N26, 4N27)	I <sub>CEO</sub>		3.5	50	nA	V <sub>ce</sub> =10 V Base Open
*Collector to emitter leakage current (4N28)				100	nA	
*Collector to base leakage current	I <sub>CBO</sub>		0.1	20	nA	V <sub>c8</sub> =10 V Emitter Open

TRANSFER CHARACTERISTICS							
DC CHARACTERISTICS	SYMBOL	MIN.	TYP.	GUAR. MAX.	UNITS	TEST CONDITIONS	
*Collector output current (a) (4N25, 4N26) (4N27, 4N28)	lo	2.0 1.0	5.0 3.0	_	mA	V <sub>CE</sub> =10 V, I <sub>F</sub> =10 mA, I <sub>B</sub> =0	
*Collector-emitter saturation	$V_{CE(SAT)}$		0.2	0.5	٧	I <sub>c</sub> =2.0 mA, I <sub>F</sub> =50 mA	

TRANSFER CHARACTERISTICS						
AC CHARACTERISTICS	SYMBOL	TYP.	UNITS	TEST CONDITIONS		
Non-saturated Collector						
Delay time	t <sub>d</sub>	0.5	μS	$R_L=100 \Omega$ , $I_c=2 \text{ mA}$ , $V_{cc}=10 \text{ V}$		
Rise time	t,	2.5	μS	(Fig. 10 and 11)		
Fall time	t,	2.6	μS	_ `		
Non-saturated Collector						
Delay time	t <sub>d</sub>	2.0	μS	$R_L=1k\Omega$ , $I_c$ 2 mA, $V_{cc}=10 \text{ V}$		
Rise time	t,	15	μS	(Fig. 10 and 11)		
Fall time	t,	15	μS	_		

<sup>\*</sup>Indicates JEDEC Registered Data.
(a) Pulse Test: Pulse Width=300  $\mu$ s, Duty Cycle  $\leq$  2.0%
(b) For this test LED pins 1 and 2 are common and Phototransistor pins 4, 5 and 6 are common.
(c) If adjusted to yield  $I_c$ =2 mA and  $I_c$ =0.7 mA RMS; Bandwidth referenced to 10 kHz.



#### **ELECTRO-OPTICAL CHARACTERISTICS**

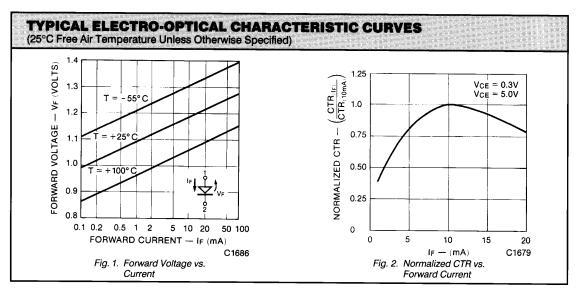
(25°C Free Air Temperature Unless Otherwise Specified) (Cont'd)

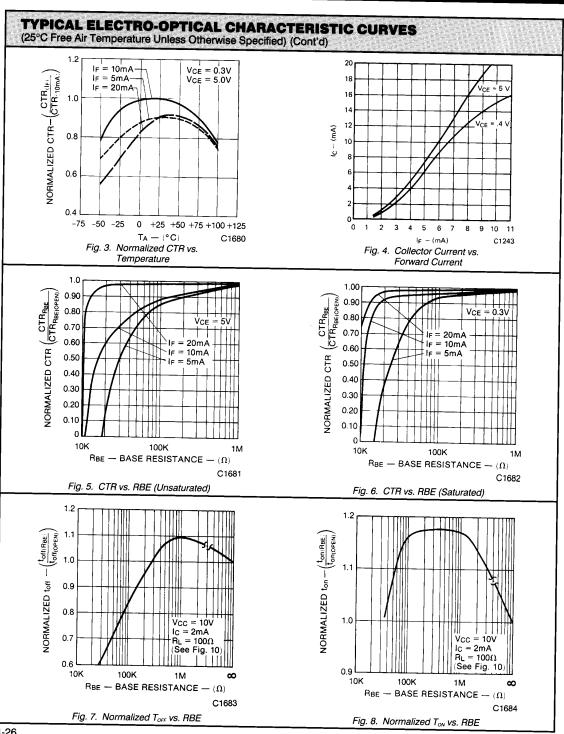
TRANSFER CHARACTERISTICS (Cont'd)						
AC CHARACTERISTICS	SYMBOL	MIN.	TYP.	GUAR. MAX.	UNITS	TEST CONDITIONS
Saturated t <sub>on</sub> (from 5 V to 0.8 V)	t₀₁ (SAT)		5		μs	$R_L=2k\Omega$ , $I_F=15$ mA, $V_{cc}=5$ V
t <sub>off</sub> (from SAT to 2.0 V)	t <sub>off</sub> (SAT)		25	100	μS	— R <sub>B</sub> =Open (Fig. 10)
Saturated t <sub>on</sub> (from 5 V to 0.8 V)	t <sub>on</sub> (SAT)		5		μs	$R_L=2k\Omega$ , $I_F=20$ mA, $V_{cc}=5$ V
t <sub>off</sub> (from SAT to 2.0 V)	t <sub>off</sub> (SAT)		18		μS	$R_B=100$ k $\Omega$ (Fig. 10)
Non-saturated Base—Collector photo diode Rise time	t,		175		ns	$R_L=1k\Omega$ , $V_{CB}=10 V$
Fall time	t,		175		ns	
Isolation voltage (b) (4N25, 4N26, 4N27, 4N28) *(4N26, 4N27) *(4N28)	V <sub>ISO</sub>	5300 1500 500		  	V V	$I_{1,0} \le 1 \mu A$ RMS, t=1 minute Peak Peak
Isolation resistance (b)			10''	16	Ω	V=500 VDC
Isolation capacitance (b)			1.3		pF	V=0, f=1.0 MHz
Bandwidth (c) (also see note 2)	B <sub>w</sub>		300		kHz	$I_c$ =2.0 mA, $R_L$ =100 $\Omega$ (Fig. 12)

\*Indicates JEDEC Registered Data.
(a) Pulse Test: Pulse Width=300 μs, Duty Cycle ≤2.0%

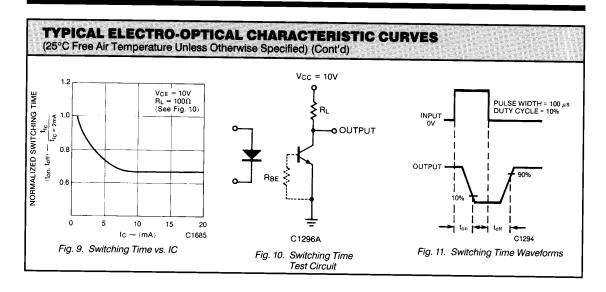
(b) For this test LED pins 1 and 2 are common and Phototransistor pins 4, 5 and 6 are common.

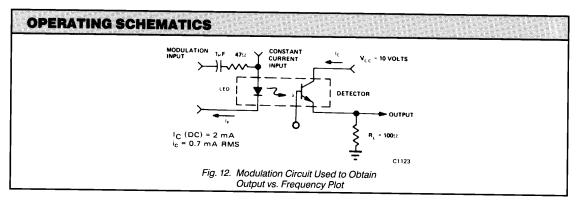
(c) If adjusted to yield I<sub>c</sub>=2 mA and i<sub>c</sub>=0.7 mA RMS; Bandwidth referenced to 10 kHz.











#### NOTES

- The current transfer ratio (I<sub>c</sub>/I<sub>F</sub>) is the ratio of the detector collector current to the LED input current with V<sub>cE</sub> at 10 volts.
   The frequency at which i<sub>c</sub> is 3dB down from the 10 kHz value.
   Rise time (t<sub>c</sub>) is the time required for the collector current to increase from 10% of its final value to 90%.
   Fall time (t<sub>c</sub>) is the time required for the collector current to decrease from 90% of its initial value to 10%.